Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/727,513	OGAWA ET AL.	
Examiner	Art Unit	
Patrick Hamo	3746	

SEARCHED				
Class	Subclass	Date	Examiner	
417	410.5	1/12/2007	PH	
417	410.1	1/14/2007	PH	
npaated		1/9/07	ph	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
				
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
417/410.1 and 410.5 searched as classified and via prior art references	1/14/2007	РН
Inventor name search: Ogawa, Nobuaki; Fujiwara, Yukihiro; Makino, Masahiko; Yoshida, Makoto; Asalda, Yasuhiro	1/12/2007	PH
ngdated	49/07	PH